

RoHS Compliant

USB Flash Drive

EH353-M Product Specifications



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Version 1.3



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Specifications Overview:

- USB3.0 Super Speed compatible, and backward compatible with USB2.0 & USB1.1 interfaces
 - USB3.0 max. transfer rate: 5 Gb/s
 - Backward compatible with 480Mbps & 12 Mbps
- Capacity
 - 8, 16, 32, 64, 128 GB
- Performance¹
 - Sequential read: up to 195 MB/s
 - Sequential write: up to 95 MB/s
- Flash Management
 - Flash bad-block management
 - Built-in hardware ECC
 - Power saving implemented
 - Global Wear Leveling
 - S.M.A.R.T.
 - Power Failure Management
- USB Bus-powered Capability
- NAND Flash Type: MLC
- MTBF: >3,000,000 hours
- Endurance (in Terabytes Written: TBW)
 - 8 GB: 22 TBW
 - 16 GB: 44 TBW
 - 32 GB: 88 TBW
 - 64 GB: 110 TBW
 - 128 GB: 273 TBW

Note

 Varies from capacities. The values for performances and power consumptions presented are typical and may vary depending on flash configurations or platform settings. The term idle refers to the standby state of the device.

- Temperature Range
 - Operating:

Standard: 0°C to 70°C

Wide: -40°C to 85°C

- Storage: -40°C to 100°C

- Power Consumption¹
 - Operating voltage: 5V
 - Active mode (Max.): 275 mA
 - Idle mode: 85 mA
- OS Support
 - Windows: WinXP/7 or later
 - Mac: 10.2.8 or later
 - Linux: 2.4.10 or later
- **Dimensions:** 59.00 x 18.40 x 9.10, unit: mm
- RoHS Compliant

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1. General Description

Apacer USB3.0 Handy Flash Drive EH353-M is a ultra high-performance flash disk drive designed to offer portable storage solutions or external memory expansion. This new generation USB flash drive is compatible with the latest USB specification – USB3.0 Super Speed, with a maximum transfer rate of 5 Gb/s. The connector is backward employable with USB2.0 and USB1.1 interfaces as well. With compliance with USB3.0 specification, this USB drive can deliver up to 195 MB/s outstanding performance. Reliability wise, the USB comes with various implementations including powerful hardware ECC engine, power saving modes, wear leveling and flash block management. This product is well suited for portable flash storage applications while operating at minimal power consumption.

2. Product Specifications

2.1 Capacity

Capacity specifications of EH353-M are available as shown in Table 2-1. It lists the specific capacity and the default numbers of heads, sectors and cylinders for each product line.

Table 2-1 Capacity Specifications

Capacity	Total bytes	Total LBA
8 GB	8,011,120,640	15,646,720
16 GB	16,039,018,496	31,326,208
32 GB	32,044,482,560	62,586,880
64 GB	64,055,410,688	125,108,224
128 GB	128,110,821,376	250,216,448

- Display of total bytes varies from operating systems. 1 GB = 1,000,000,000 bytes; 1 sector = 512 bytes.
- LBA count addressed in the table above indicates total user storage capacity and will remain the same throughout the lifespan of the device. However, the total usable capacity of the SSD is most likely to be less than the total physical capacity because a small portion of the capacity is reserved for device maintenance usages.

2.2 Performance

Performance of EH353-M is listed below in Table 2-2.

Table 2-2 Performance Specifications

Capacity Performance	8 GB	16 GB	32 GB	64 GB	128	GB
Sequential Read (MB/s)	95	190	190	185	190	195
Sequential Write (MB/s)	29	55	45	95	95	80

- Results may differ from various flash configurations or host system setting.
- Sequential read/write is based on CrystalDiskMark 5.2.1 with file size 1,000MB.
- Values for 128GB on the left are measured on 512Gb x2 while those on the right are measured on 1Tb x1.

2.3 Environmental Specifications

Environmental specifications of EH353-M product are shown in Table 2-3.

Table 2-3 Environmental Specifications

Item	Specifications
Operating temp.	0°C to 70°C (Standard); -40°C to 85°C (Wide)
Non-operating temp.	-40°C to 100°C
Operating vibration	7.69 GRMS, 20~2000 Hz/random (compliant with MIL-STD-810G)
Non-operating vibration	4.02 GRMS, 15~2000 Hz/random (compliant with MIL-STD-810G)
Operating shock	50G, 11ms/half-sine (compliant with MIL-STD-202G)
Non-operating shock	1,500G, 0.5ms/half-sine (compliant with MIL-STD-883K)

Note: This Environmental Specification table indicates the conditions for testing the device. Real world usages may affect the results

2.4 Mean Time Between Failures (MTBF)

Mean Time Between Failures (MTBF) is predicted based on reliability data for the individual components in EH353-M. The prediction result for EH353-M is more than 3,000,000 hours.

Note: The MTBF is predicated and calculated based on "Telcordia Technologies Special Report, SR-332, Issue 3" method.

2.5 Certification and Compliance

EH353-M complies with the following standards:

- CE (Criteria B)
- UKCA
- FCC
- RoHS
- MIL-STD-810G

2.6 Endurance

The endurance of a storage device is predicted by TeraBytes Written based on several factors related to usage, such as the amount of data written into the drive, block management conditions, and daily workload for the drive. Thus, key factors, such as Write Amplifications and the number of P/E cycles, can influence the lifespan of the drive.

Table 2-4 Endurance Specifications

Capacity	TeraBytes Written
8 GB	22
16 GB	44
32 GB	88
64 GB	110
128 GB	273

Notes:

- The estimated values are based on sequential write behavior.
 (Apacer EDTest Tool, test mode sequential data pattern 100.00% of disk space with 128K)
- Flash vendor guaranteed MLC P/E cycle: 3K.
- WAF may vary from capacity, flash configurations and writing behavior on each platform.
- 1 Terabyte = 1,024 GB.

3. Flash Management

3.1 Performance-optimized USB Controller

The heart of EH353-M is the USB controller, which translates standard USB signals into the data and controls of the flash media. This proprietary USB controller is specifically designed to attain high data throughput from host to flash.

3.2 Power Saving Implemented

The internal controller of the USB model is designed with power saving implementations, allowing the device to operate at low power consumption.

3.3 Program RAM Architect

The internal Program RAM implementation allows the host to upgrade firmware codes anytime when needed.

3.4 Error Correction Code (ECC)

Flash memory cells can deteriorate with use, which might lead to random bit errors in the stored data. Thus, this USB applies the BCH ECC Algorithm, which can detect and correct errors occurring during Read process, ensure data to be read correctly, as well as protect data from corruption. This device can correct up to 39bit/1K data.

3.5 Flash Block Management

Current production technology is unable to guarantee total reliability of NAND flash memory array. When a flash memory device leaves factory, it comes with a minimal number of initial bad blocks during production or out-of-factory as there is no currently known technology that produce flash chips free of bad blocks. In addition, bad blocks may develop during program/erase cycles. Since bad blocks are inevitable, the solution is to keep them in control. Apacer flash devices are programmed with ECC and block mapping technique to reduce invalidity or error. Once bad blocks are detected, data in those blocks will be transferred to free blocks and error will be corrected by designated algorithms.

3.6 Power Failure Management

Power Failure Management plays a crucial role when power supply becomes unstable. Power disruption may occur when users are storing data into the SSD, leading to instability in the drive. However, with Power Failure Management, a firmware protection mechanism will be activated to scan pages and blocks once power is resumed. Valid data will be transferred to new blocks for merging and the mapping table will be rebuilt. Therefore, data reliability can be reinforced, preventing damage to data stored in the NAND Flash.

3.7 Global Wear Leveling

Flash memory can be erased a limited number of times, This number is called the erase cycle limit, or write endurance limit, The erase cycle limit applies to each individual erase block in the flash device.

In a typical application, and especially if a file system is used, specific pages are constantly updated (e.g., the page that contains the FAT, registry, etc.). Without any special handling, these pages would wear out more rapidly than other pages, reducing the lifetime of the entire flash.

To overcome this inherent deficiency, Apacer's EH353-M uses Global Wear Leveling algorithm. This algorithm ensures that consecutive writes of a specific sector are not written physically to the same page in the flash. This spreads flash media usage evenly across all pages, thereby maximizing flash lifetime.

The Global Wear Leveling mechanism provides write/erase cycles for reliable data storage over an extended period.

3.8 S.M.A.R.T.

S.M.A.R.T. is an abbreviation for Self-Monitoring, Analysis and Reporting Technology, a self-monitoring system that provides indicators of drive health as well as potential disk problems. It serves as a warning for users from unscheduled downtime by monitoring and displaying critical drive information. Ideally, this should allow taking proactive actions to prevent drive failure and make use of S.M.A.R.T. information for future product development reference.

Table 3-1 SMART Attribute ID List

ID (Hex)	Attribute Name
162 (0xA2)	Spare Block Count
163 (0xA3)	Maximum Erase Count
164 (0xA4)	Average Erase Count
166 (0xA6)	Total Later Bad Block Count
167 (0xA7)	Protect Mode

4. Electrical Specifications

4.1 Absolute Stress Rating

Table 4-1 lists the absolute stress rating for EH353-M.

Caution: Absolute Maximum Stress Ratings – Applied conditions greater than those listed under "Absolute Maximum Stress Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these conditions or conditions greater than those defined in the operational sections of this data sheet is not implied. Exposure to absolute maximum stress rating conditions may affect device reliability.

Table 4-1 Absolute Stress Rating

Item	Range
Required power supply	4.5-5.5V
Operating temperature	0°C to 70°C (Standard); -40°C to 85°C (Wide)
Storage temperature	-40°C to 100°C

4.2 Power Consumption

Table 4-2 lists the power consumption for EH353-M.

Table 4-2 Power Consumption (Unit: mA)

Capacity Mode	8 GB	16 GB	32 GB	64 GB	128	3 GB
Active (Max.)	150	270	265	275	265	175
ldle	50	85	80	80	55	35

Notes:

- All values are typical and may vary depending on flash configurations or host system settings.
- Power consumption is measured using CrystalDiskMark 5.2.1.
- Values for 128GB on the left are measured on 512Gb x2 while those on the right are measured on 1Tb x1.

5. Mechanical Specifications

Table 5-1 Dimensions

Parameter	Unit	8GB	16GB	32GB	64GB	128GB
Length				59.00 ± 0.2		
Width	mm			18.40 ± 0.2		
Height				9.10 ± 0.2		

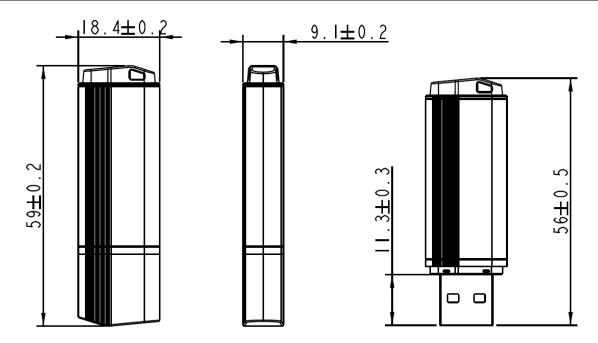
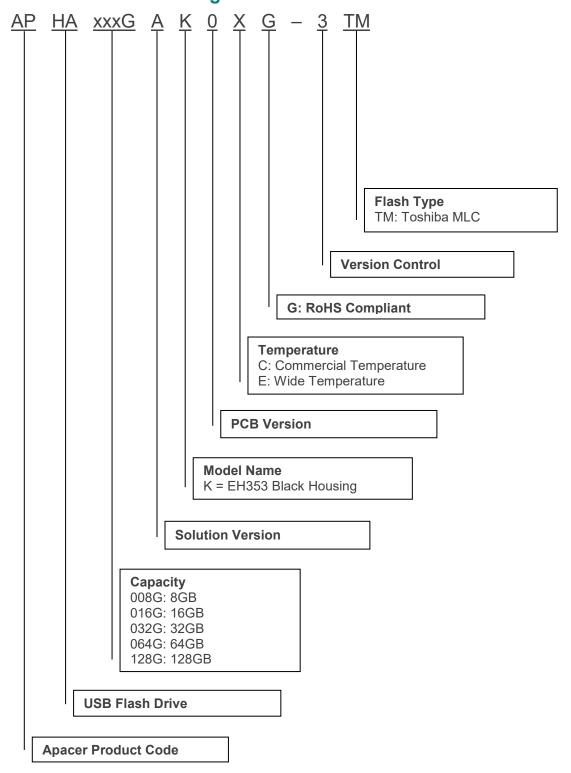


Figure 5-1 Physical Dimensions

6. Product Ordering Information

6.1 Product Code Designations



6.2 Valid Combinations

The following table lists the available models of the EH353-M series which are in mass production or will be in mass production. The part number with one asterisk represents the SSD manufactured based on $512Gb \times 2$ while that with two asterisks based on $1Tb \times 1$.

Consult your Apacer sales representative to confirm availability of valid combinations and to determine availability of new combinations.

Capacity	Standard Temperature	Wide Temperature	
8GB	8GB APHA008GAK0CG-3TM APHA008GAK		
16GB	APHA016GAK0CG-3TM	APHA016GAK0EG-3TM	
32GB	APHA032GAK0CG-3TM	32GAK0CG-3TM APHA032GAK0EG-3TM	
64GB	APHA064GAK0CG-3TM	APHA064GAK0EG-3TM	
128GB APHA128GAK0CG-3TM		APHA128GAK0EG-3TM*	
120GB	APHA120GARUCG-31M	APHA128G4KCEG-3TM**	

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Revision History

Revision	Description	Date
1.0	Official release (with content structure update)	8/27/2020
1.1	Removed support for orange housing	9/17/2020
1.2	Updated Table 4-1 by changing storage temp. from 0°C to 100°C to -40°C to 100°C	5/24/2022
	- Updated sequential read performance on Specifications Overview page	
	- Removed 8GB performance and power consumption measured on 32Gb x2 from Table 2-2 and Table 4-2	
1.3	- Modified non-operating vibration specification from sine to random at Table 2-3	12/22/2022
	- Added UKCA, FCC, RoHS and MIL-STD-810G to 2.5 Certification and Compliance	
	- Added Table 3-1 SMART Attribute ID List	

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